

Search Notes

Application No.

10/620,543

Examiner

David W. Scheuermann

Applicant(s)

TAKAHASHI ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	40MM		
	42		
	89		
	91		
	239		
	240		
	241		
	242	2/16/05	DS

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consult T. Nguyen Search	1/3/05	DS
Consult T. Nguyen allowable claims	2/17	DS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner